

**Search Notes**

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Examiner

EDMUND H. LEE

Applicant(s)/Patent under  
Reexamination

YAMAKAWA ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
UPDATED		4/30/2007	EHL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
264	162,161	4/30/2007	EHL
83	13	↓	↓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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